

PCN Number:		20121210005		PCN Date:		07/29/2014	
Title:		X035 Automotive Cu Wire Conversion for nFBGA					
Customer Contact:		PCN_ww_admin_team@list.ti.com		Phone:		+1(214)480-6037	
Dept:		Quality Services					
Proposed 1st Ship Date:		01/29/2015		Estimated Sample Availability:		Date provided at sample request	
Change Type:							
<input type="checkbox"/>	Assembly Site	<input type="checkbox"/>	Design	<input type="checkbox"/>	Wafer Bump Site		
<input type="checkbox"/>	Assembly Process	<input type="checkbox"/>	Data Sheet	<input type="checkbox"/>	Wafer Bump Material		
<input checked="" type="checkbox"/>	Assembly Materials	<input type="checkbox"/>	Part number change	<input type="checkbox"/>	Wafer Bump Process		
<input type="checkbox"/>	Mechanical Specification	<input type="checkbox"/>	Test Site	<input type="checkbox"/>	Wafer Fab Site		
<input type="checkbox"/>	Packing/Shipping/Labeling	<input type="checkbox"/>	Test Process	<input type="checkbox"/>	Wafer Fab Materials		
				<input type="checkbox"/>	Wafer Fab Process		
PCN Details							
Description of Change:							
Texas Instruments Incorporated is announcing the qualification for Cu Wire conversion of ANTARES F035							
	From		To				
Bond Wire	Au		Cu				
Reason for Change:							
Continuity of supply. 1) To align with world technology trends and use wiring with enhanced mechanical and electrical properties. 2) Maximize flexibility within our Assembly/Test production sites 3) Copper wire is easier to obtain and stock.							
Anticipated impact on Fit, Form, Function, Quality or Reliability (positive / negative):							
No anticipated impact.							
Changes to product identification resulting from this PCN:							
None							
Product Affected:							
S5LS10106ASZWTQQ1		S5LS10206ASZWTQQ1		S5LS20206ASZWTQQ1			
S5LS10116ASZWTQQ1		S5LS10216ASZWTQQ1		S5LS20216ASZWTQQ1			



TI Information
Selective Disclosure

Automotive New Product Qualification Summary (As per AEC-Q100 and JEDEC Guidelines)

Antares nfBGA Auto Package Qualification For Cu Wire Approved 02/03/2014

Product Attributes

	Qual Device: Antares	QBS Device: Mira+
Die Attributes		
Wafer Fab Site	DMOS5	DMOS5
Die Revision	-	-
Package Attributes		
Assembly Site	PHI (TIPI)	PHI (TIPI)
Package Type	nfBGA	nfBGA
Package Designator	ZWT	ZWT
Ball/Lead Count	337	337

- QBS: Qual By Similarity

- Qual Device TMS320DM6437ZWTQ6 is qualified at LEVEL3-260C

- Qual Device TMS320DM6437ZWTQ6 (CONTROL) is qualified at LEVEL3-260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Type	#	Test Name / Condition	Duration	Qual Device: S5LS10106ASZWTQQ1	QBS Device: S5PC61ACZFEQRB
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Test Group A - Accelerated Environment Stress Test

PC	A1	PreCon Level 3	Preconditioning: SMD only; Moisture Preconditioning for THB/HAST, AC/UHST, TC, HTSL, and HTOL	Performed on <u>ALL</u> SMD devices prior to THB/HAST, AC/UHST, TC and PTC	
HAST	A2	THB, 85C/85%RH	1000 Hours	-	3/231/0
UHAST	A3	Unbiased HAST 130C/85%RH	96 Hours	3/240/0	-
TC	A4	Temperature Cycle, - 55/125C	1600 Cycles	3/231/0	-
HTSL	A6	High Temp Storage Bake 150C	1000 Hours	3/150/0	-

Test Group C - Package Assembly Integrity Tests

WBS	C1	Wire Bond Shear (Ppk > 1.67 and Cpk > 1.33)	30 Bonds / 5 Parts Minimum	Pass	-
WBP	C2	Wire Bond Pull (Ppk > 1.67 and Cpk > 1.33)	30 Bonds / 5 Parts Mimum	Pass	-
SD	C3	Surface Mount Solderability >95% Lead Coverage	1/15/0 Minimum	Pass	-
PD	C4	Physical Dimensions (Cpk>1.33 Ppk>1.67)	1/10/0 Minimum	Pass	-

SBS	C5	Solder Ball Shear (Ppk > 1.67 and Cpk > 1.33)	5 Balls / 10 Parts Minimum	Pass	-
LI	C6	Lead Integrity	10 Leads / 5 Parts Minimum	Pass	-
Test Group E - Electrical Verification					
HBM	E2	ESD – HBM	EEP2000V/25C/130C/-40C	1/22/0	-
CDM	E3	ESD – CDM	+/- 500V Minimum on all pins 750V Minimum for corner pins	1/5/0 1/5/0	-
LU	E4	Latchup	+/- 100mA	1/6/0	-
ED	E5	Electrical Distribution (Cpk > 1.67, Ppk > 1.67)	(Test across recommended operating temperature range)	QBS To Current BOM	-

A1 (PC): Preconditioning:

Performed for THB, Biased HAST, AC, uHAST & TC samples, as applicable.

Ambient Operating Temperature by Automotive Grade Level:

Grade 0 (or A): -40°C to +150°C
Grade 1 (or Q): -40°C to +125°C
Grade 2 (or T): -40°C to +105°C
Grade 3 (or I) : -40°C to +85°C
Grade 4 (or C): -40°C to +70°C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

Room/Hot/Cold : HTOL
Room/Hot : THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU
Room : AC/uHAST

Green/Pb-free Status: Qualified Pb-Free(SMT) and Green

TI Qualification ID: 20130220-78404

TI Qualification ID: 20130221-78462

Quality and Reliability Data Disclaimer

TI assumes no liability for applications assistance or customer product design. Customers are responsible for their products and applications using TI components. To minimize the risks associated with customer products and applications, customer should provide adequate design and operating safeguards. Quality and reliability data provided by Texas Instruments is intended to be an estimate of product performance based upon history only. It does not imply that any performance levels reflected in such data can be met if the product is operated outside the conditions expressly stated in the latest published data sheet or agreed-to customer specification for a device.

Reliability data shows characteristic failure mechanisms of the specific environmental stress as documented in the industry standards for each stress condition.

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

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